Se	arch No	tes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/535,304	CHO ET AL.
Examiner	Art Unit
Leslie P. Cruz	2826

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH	STRATEGY)
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EAST (See Search History Printouts)	11/22/2006	LPC
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